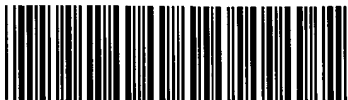


**Search Notes**

Application/Control No.

10/664,296

Examiner

Natalia Figueroa

Applicant(s)/Patent under  
Reexamination

HIRANO ET AL.

Art Unit

2651

**SEARCHED**

Class	Subclass	Date	Examiner
360	245.3- 245.7	10/29/2004	NFM
360	240	10/29/2004	NFM
360	244	10/29/2004	NFM
360	39,55	10/29/2004	NFM
360	31	10/29/2004	NFM
360	244.1	11/1/2004	NFM

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Kin Wong (Double Patenting Matters to application 10/664,296)	10/27/2004	NFM
Andrew Sniezek (Doub. Pat. Matters and sub-classes 245.3-245.7, sensor in flexure hard if any?)	10/28/2004	NFM
EAST Search	10/28/2004	NFM
EAST Search	10/29/2004	NFM
NPL (Patent Abstracts of Japan)	10/31/2004	NFM
James habermehl (search in G11B021)	10/31/2004	NFM
Robert Tupper (Xref 360/244.1, 245.3)	11/1/2004	NFM